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**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re patent application of: Noboru Ichinose, et al.

Serial No.: 10/567,369

Group Art Unit: 2814

Filing Date: May 15, 2006

Examiner: Salerno, Sarah Kate

For: SEMICONDUCTOR LAYER WITH A  $\text{Ga}_2\text{O}_3$  SYSTEM

Honorable Commissioner for Patents  
Alexandria, VA 22313-1450

**INFORMATION DISCLOSURE STATEMENT**

Sir:

Under the provisions of 37 CFR §1.97 through §1.98 and pursuant to applicant's duty of disclosure under 37 CFR §1.56, applicant respectfully brings the following documents cited in the Japanese Office Action dated July 20, 2010 in a counterpart foreign application and listed on the attached form PTO-1449, to the attention of the Examiner in charge of the above-identified application. Copies of the listed documents are provided herewith for the convenience of the Examiner.

I hereby certify that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement.

In compliance with the requirements of 37 CFR §1.98(a)(3), as a concise statement of relevance, as it is presently understood by the individual designated in 35 U.S.C. §1.56(c) most knowledgeable about the content of the information, the undersigned attorney of record submits a translation of portions of an official action by a foreign examiner in which the reference was cited. The relevance to the pending U.S. patent application is that the reference was cited in a foreign patent application on the same subject matter. However, no independent analysis of the reference, the accuracy of the statement of the foreign examiner or the claims of the foreign application under the laws of that country or the United States relative to the subject matter claimed in the present application has been made, the present

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understanding of the contents thereof by the undersigned being based on the translation of the foreign examiner's comments submitted herewith. Further, English abstracts are attached to each of the foreign references and an English translation is attached to JP 2002-270525 A1.

Further, it is noted that U.S. Patent Publication No. 2002/0058162 A1 is the U.S. equivalent of Japanese Patent Application No. 2002-187800 A1.

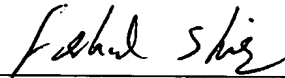
This citation does not constitute an admission that the references are relevant or material to the claims. They are only cited as constituting related art of which the applicant is aware.

Submitted herewith is the IDS fee of \$180.00.

It is respectfully requested that the listed references be considered by the Examiner and formally made of record in this application.

Please charge any deficiencies in fees and credit any overpayment of fees to Attorney's Deposit Account No. 50-0481.

Respectfully submitted,



Farhad Shir, Ph.D.  
Registration No. 59,403

Sean M. McGinn, Esq.  
Registration No. 34,386

Date: 10/1/10

**McGinn Intellectual Property Law Group, PLLC**  
Intellectual Property Law  
8321 Old Courthouse Road, Suite 200  
Vienna, VA 22182-3817  
(703) 761-4100  
Customer No. 21254